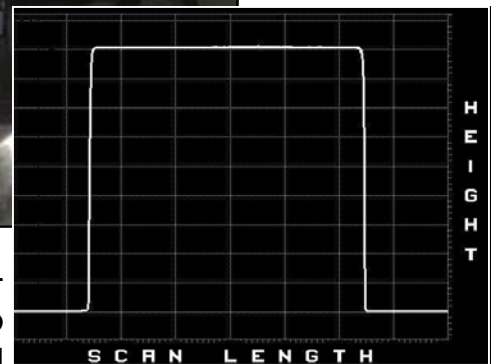
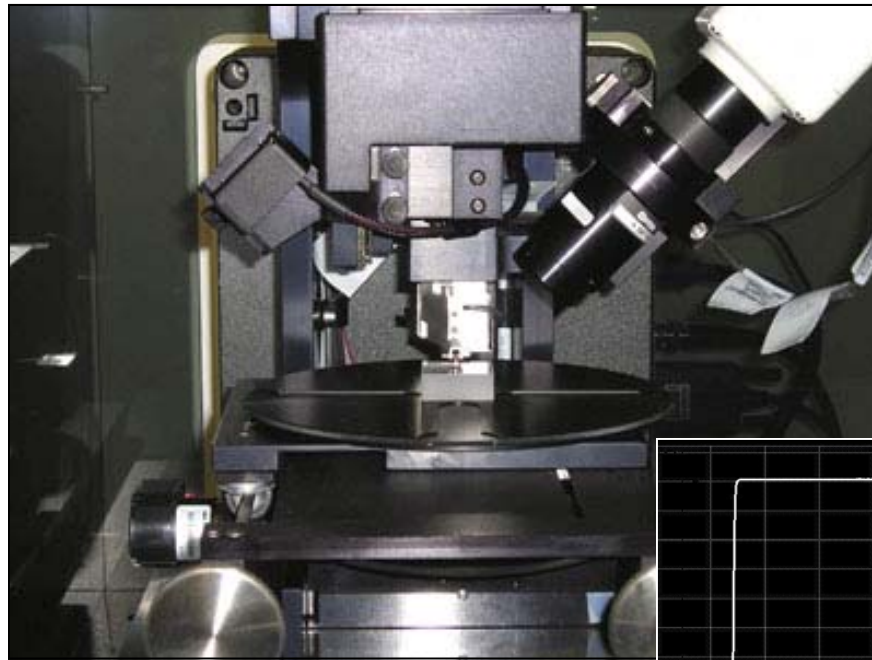


DEKTAK 6M SURFACE PROFILER

Instrument Quick Stats

- Vertical resolution on the angstrom scale.
- Stage rotates 360°.
- Equipped with two interchangeable diamond tip styli.
- Stylus tracking force is adjustable from 1-15mg.
- Measures Z-heights ranging from 50Å to 262µm.
- Horizontal scan lengths may range from 50µm to 30mm.
- Accommodates samples up to 1.25" thick.
- Capable of measuring samples up to 6" wide.
- Maximum sample weight: 1.5 lbs.
- Automated program can run up to 10,000 consecutive scans.



Surface profiling is a non-destructive analytical technique that can be used to measure topographical features on a solid sample. Data is collected by tracing a stylus across the sample surface and measuring the changes in its vertical motion. The Dektak 6M Surface Profiler (above) is a stylus profilometer with resolution on the angstrom scale. Topographical properties such as roughness, step height (above right) and waviness can be accurately evaluated. The standard diamond-tip stylus, 12.5µm diameter, can easily be exchanged with a 2.5µm stylus for studies which require a sharper tip. The instrument is capable of measuring from 50Å to 262µm vertically and from 50µm to 30mm horizontally.

Samples examined by the surface profiler can be polymer films, thin film coatings or metal surfaces. It is, however, possible to accommodate a wide variety of specimens as long as they are or can be mounted onto a substrate.

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